

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10660796	NAGAO, SEIJI
	Examiner	Art Unit
	Carter, Aaron W	2624

SEARCHED

Class	Subclass	Date	Examiner
382	141-152	12/19/06	AWC
348	125-134, 86-112	12/19/06	AWC
356	237.1-237.6	12/19/06	AWC
705	4	12/19/06	AWC
Updated Search		2/9/07	AWC

SEARCH NOTES

Search Notes	Date	Examiner
EAST Text Search (USPAT, PGPUB) See Search History Printout	12/19/06	AWC
Inventor Name Search (See PALM Search History Printout, Check Marks Indicate Applications Considered)	12/19/06	AWC
IEEE Search (See Search History Printout)	12/19/06	AWC
Interference Search History	2/9/07	AWC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
PGPUB Text Search		2/9/07	AWC